

3" PMT Test: Uniform light @IPMU

TYPE: R14374 (Hamamatsu Photonics K.K.)

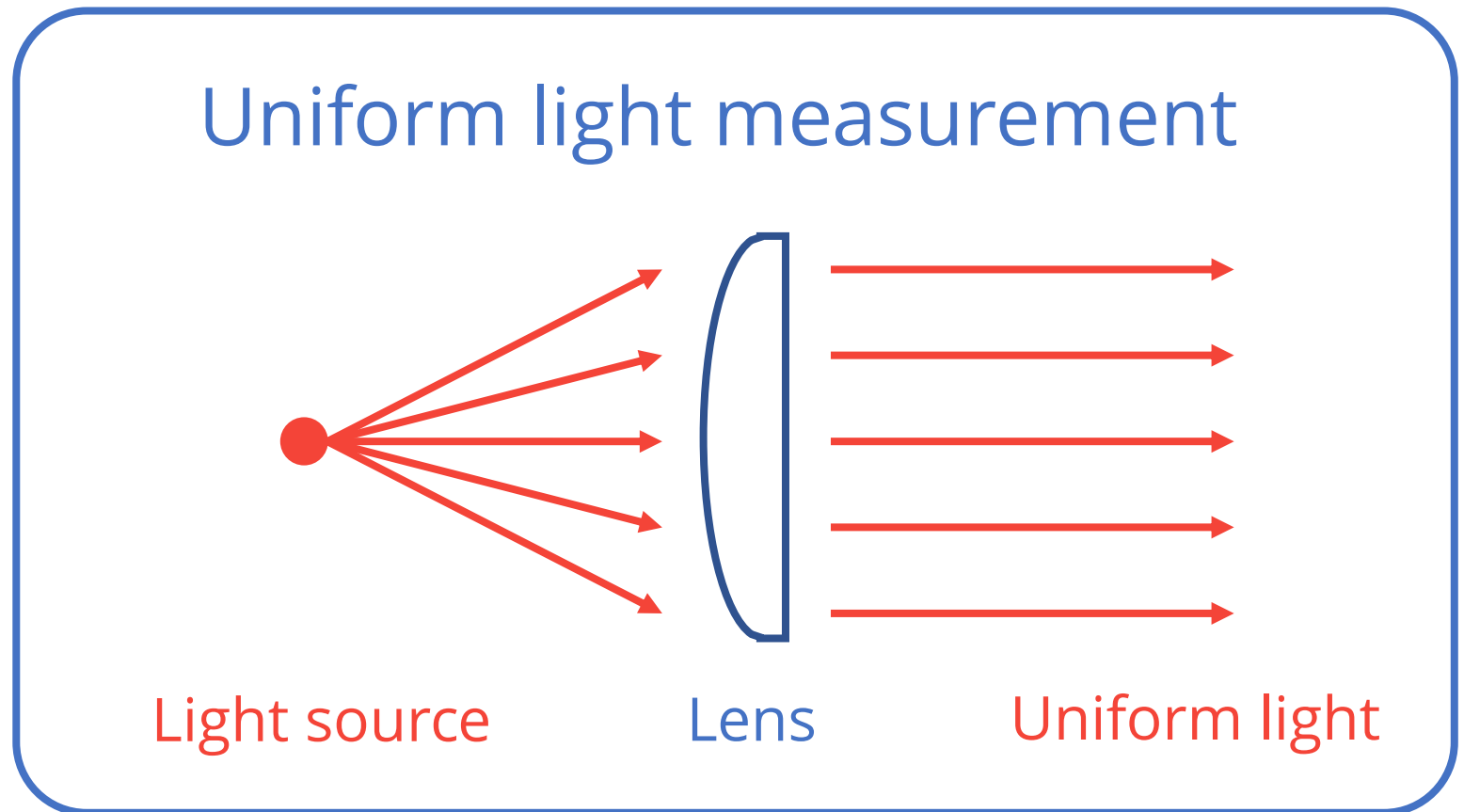
January 28th, 2019

Haruya Morikawa (Tokyo Institute of Technology)

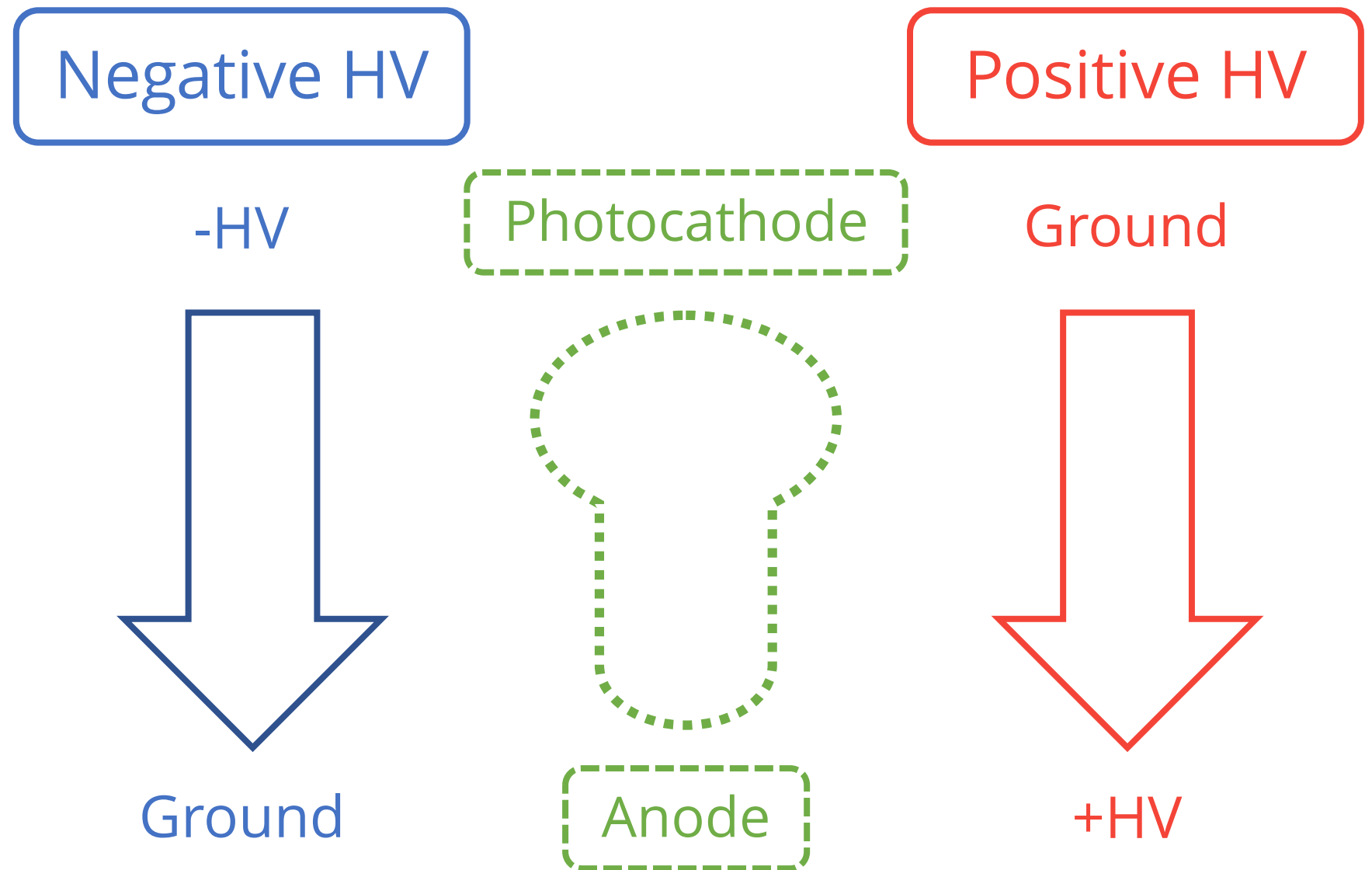
Benjamin Quilain (Kavli IPMU)

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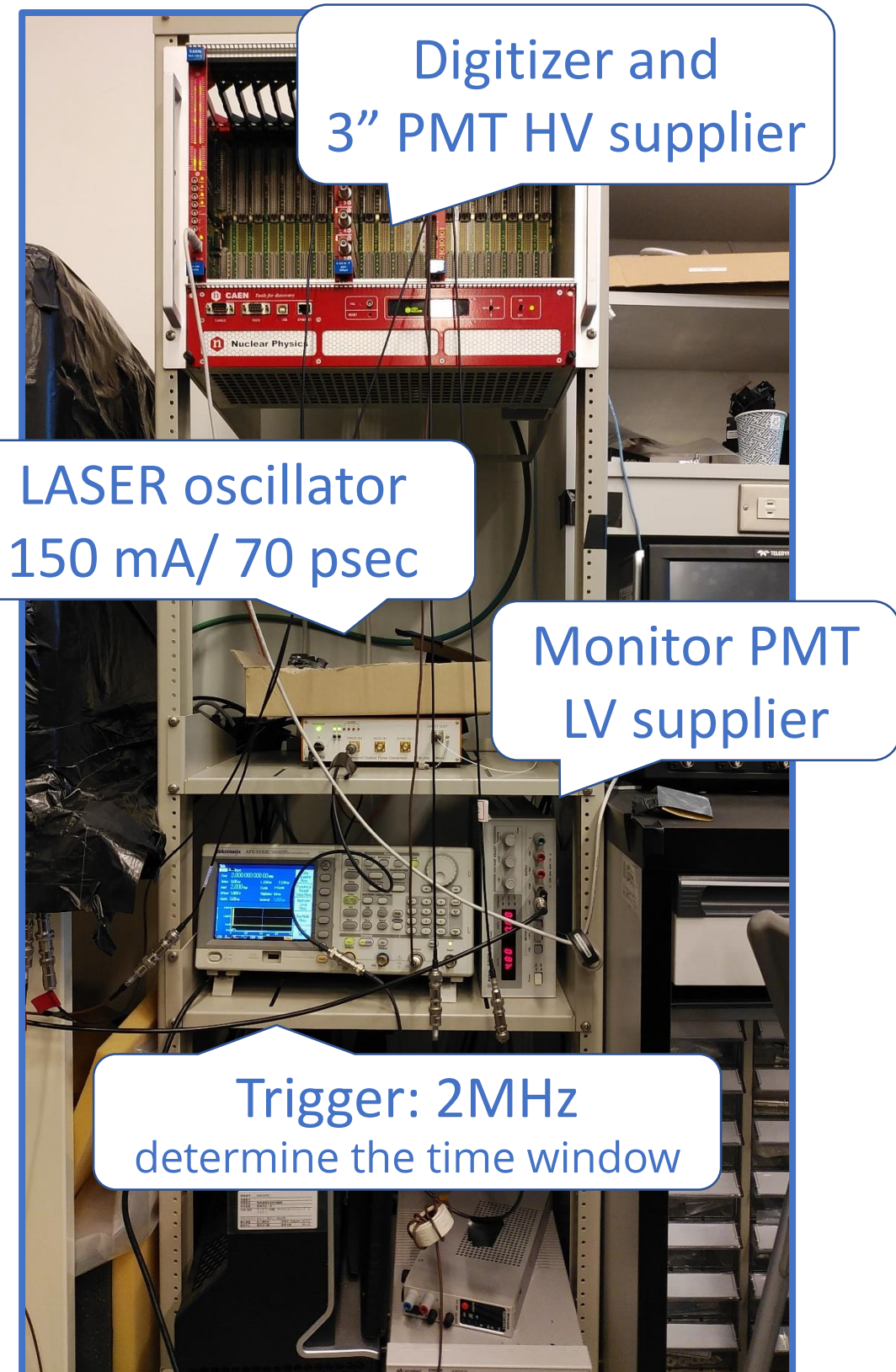
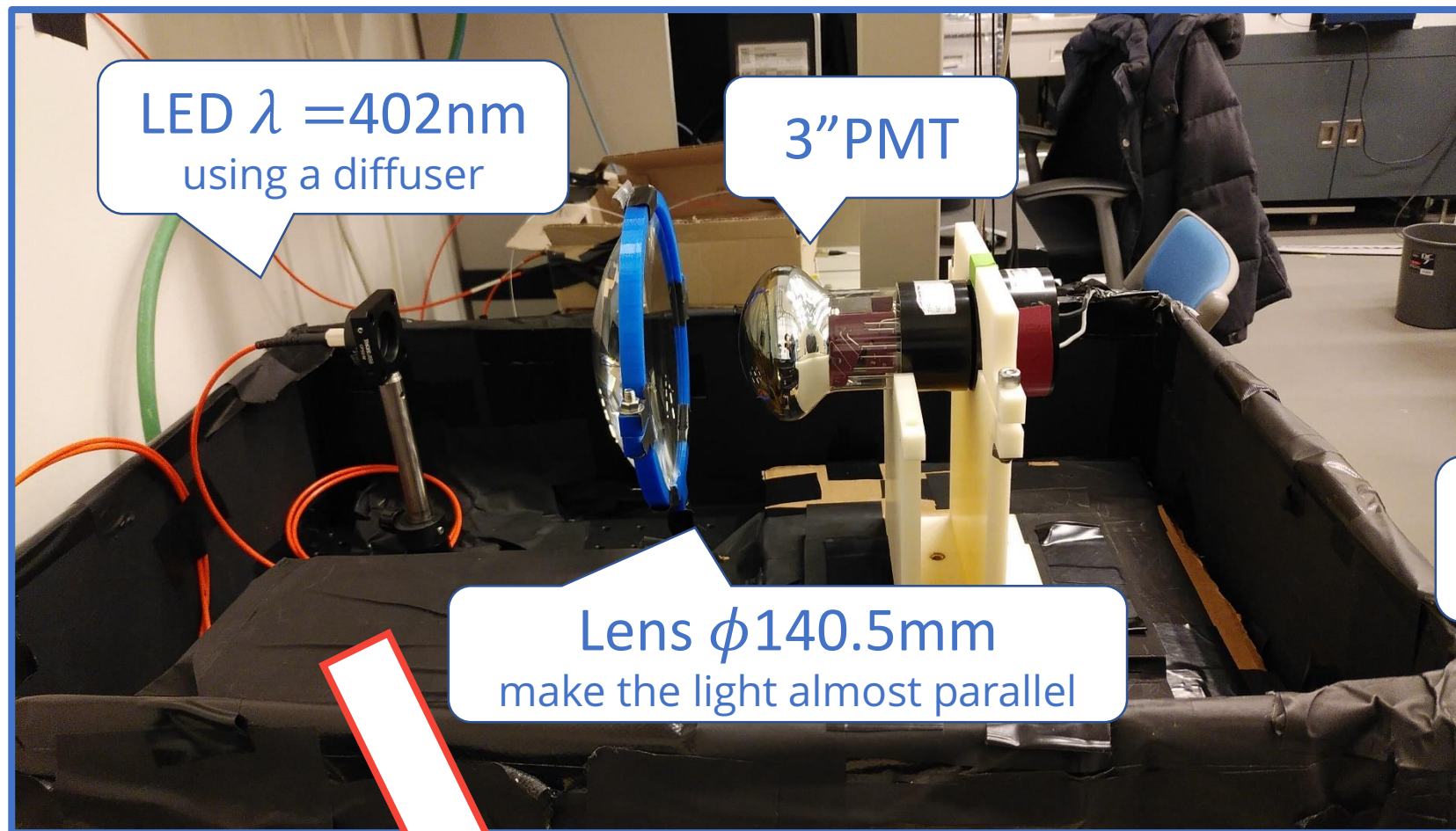


3" PMT: R14374

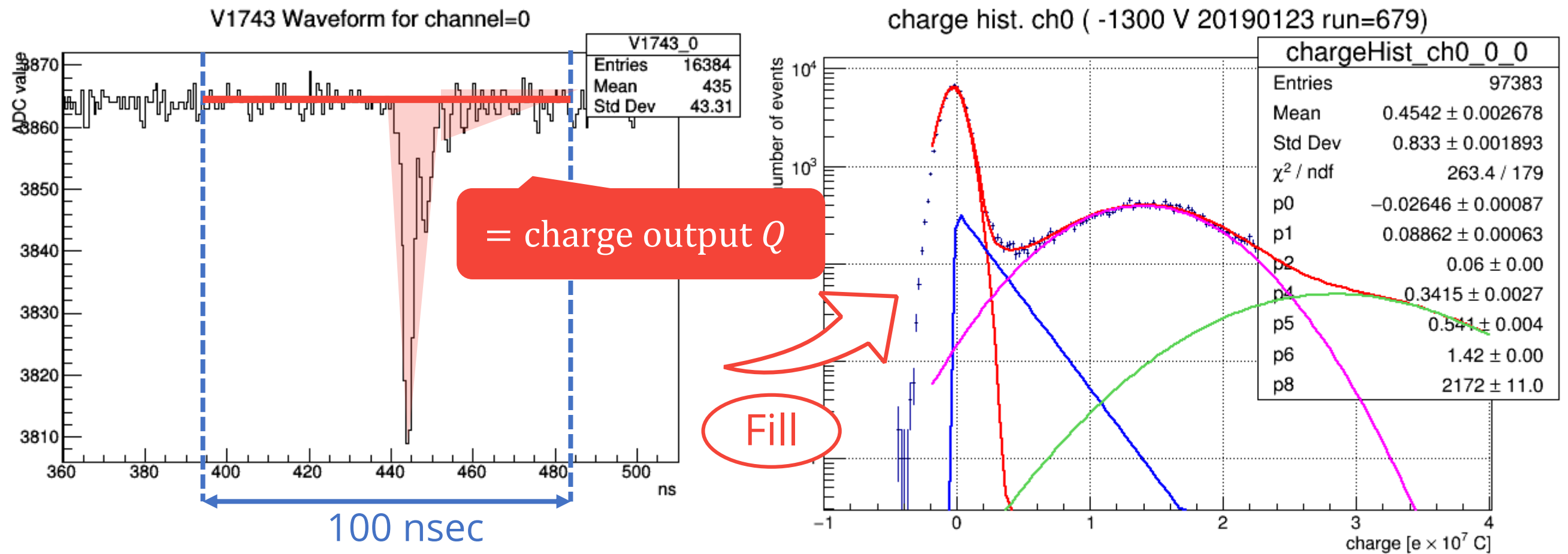


- R14374: produced by Hamamatsu Photonics K.K.
 - Dynode type: Circular and Linear-focused type
- Test on two serial numbers: BC0035 and BC0038

Setting @IPMU

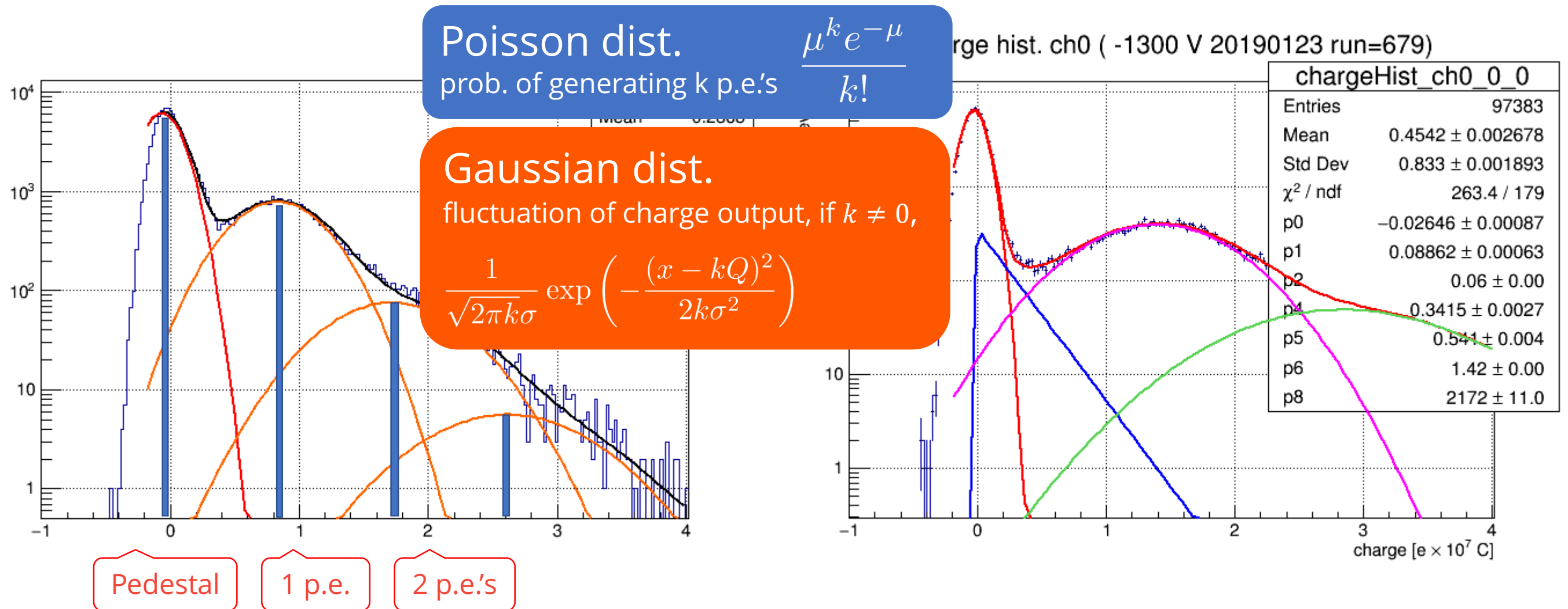


Charge histogram



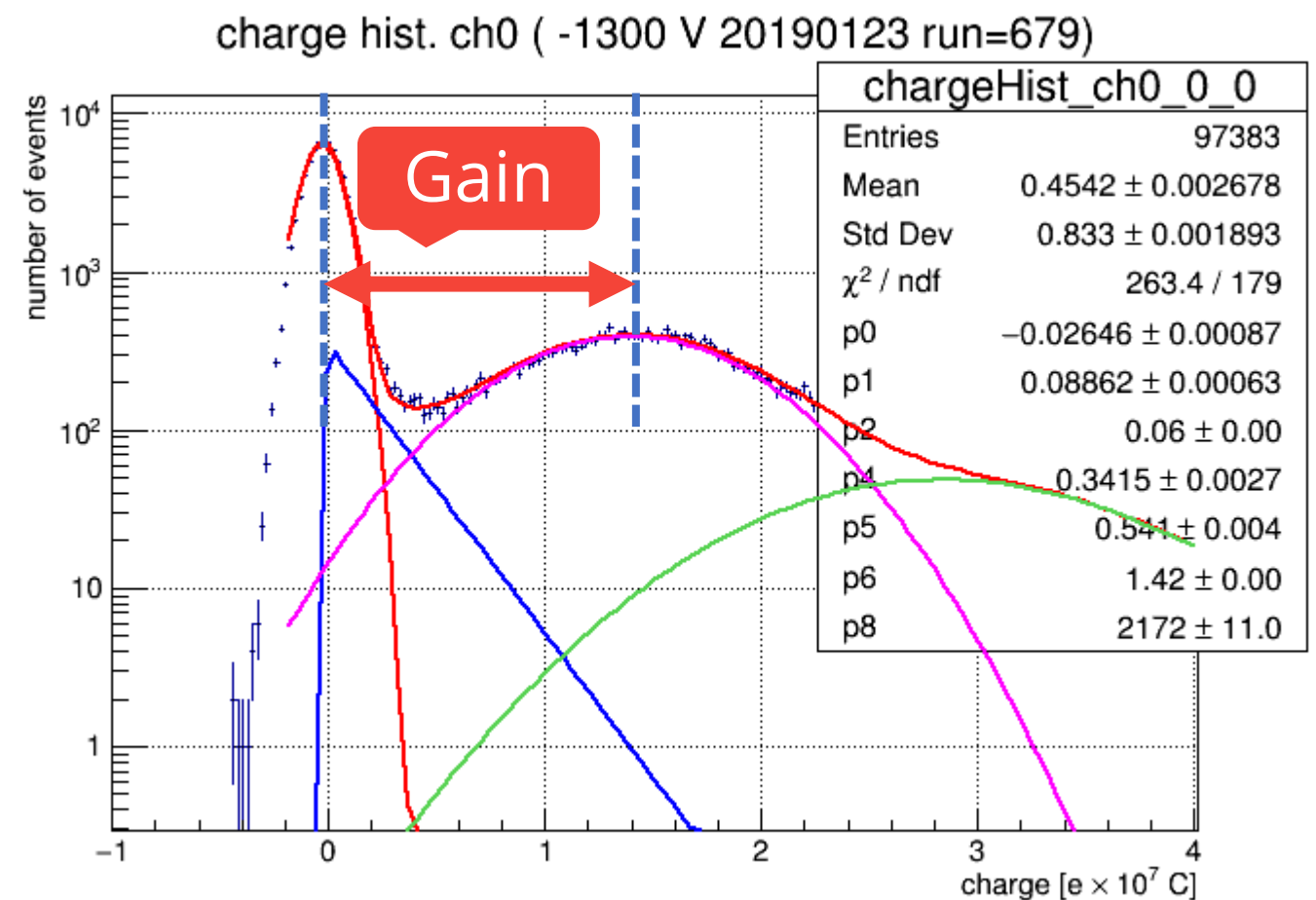
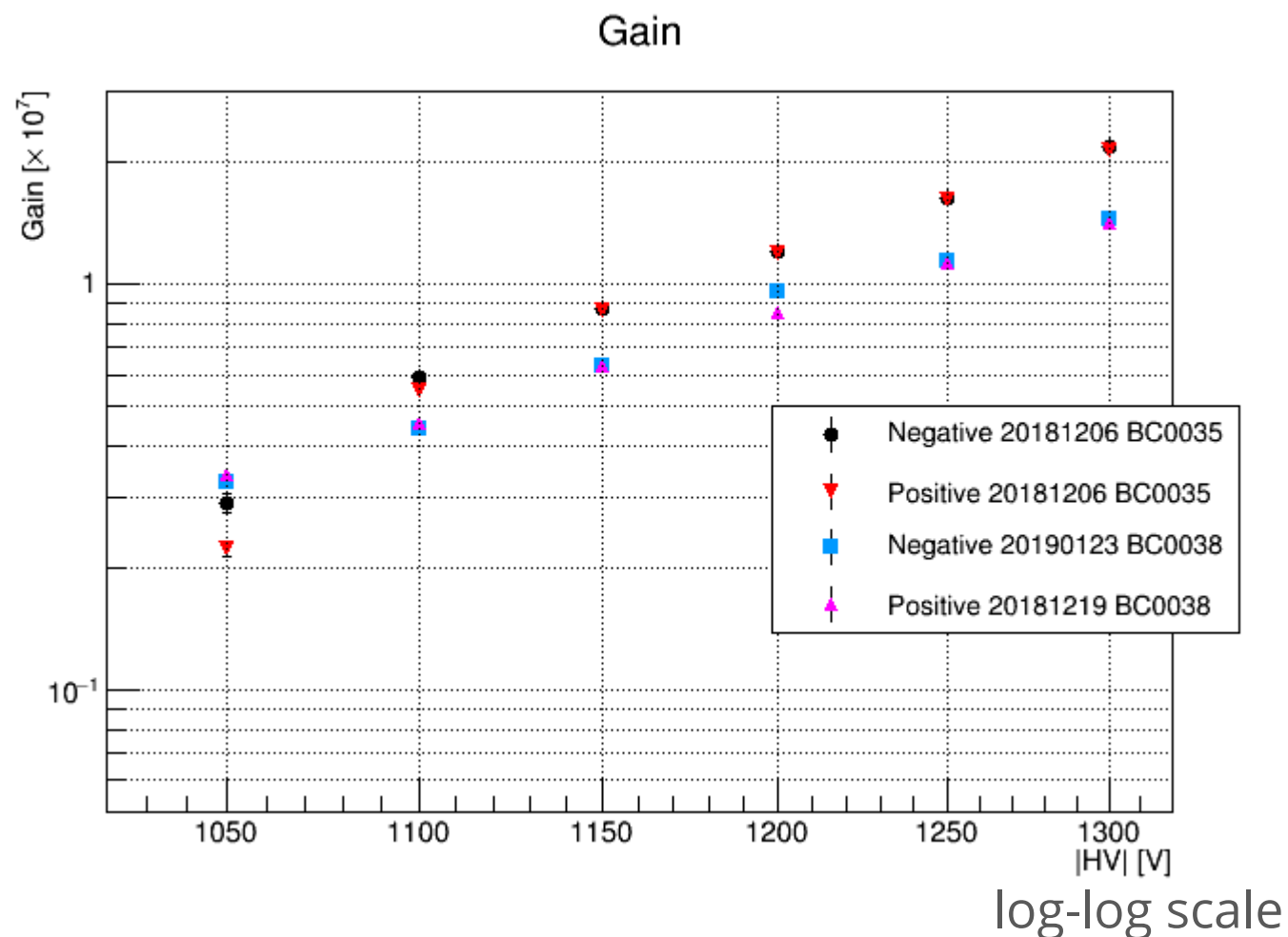
- event by event..
 1. baseline of integral: the mean of noise
 2. integrate in 100 nsec region
 3. convert integral value to charge, then fill it

Charge histogram: distribution



- charge distribution = Poisson dist. * Gaussian dist.
 - Poisson dist. : prob. of generating $k (\geq 0)$ photoelectrons on photocathode
 - Gaussian dist. : fluctuation of charge output at each event
 - 0 p.e. distribution (so-called "pedestal") has different σ from $k (\neq 0)$ p.e.'s distribution. (σ is Gaussian's σ .)

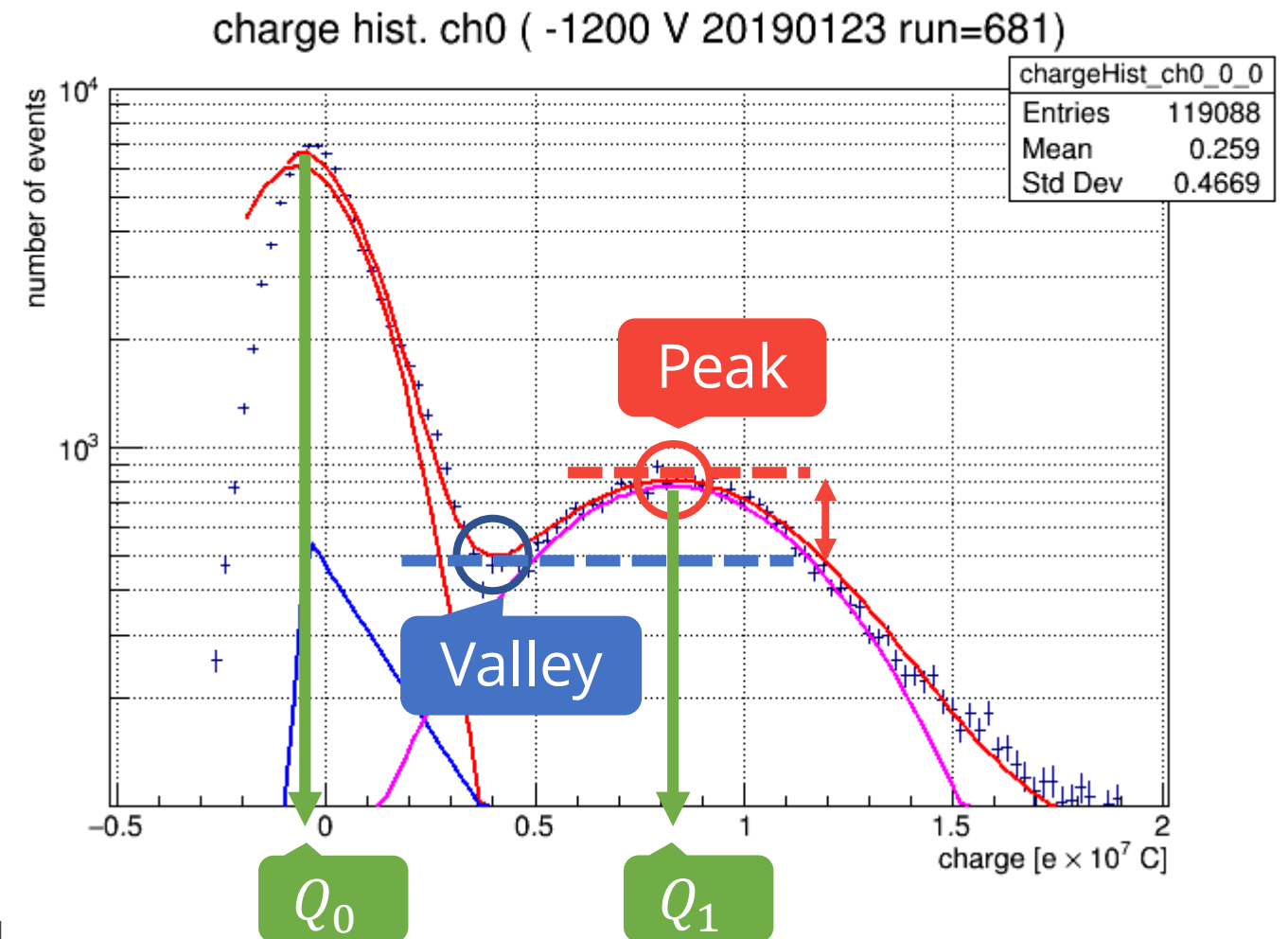
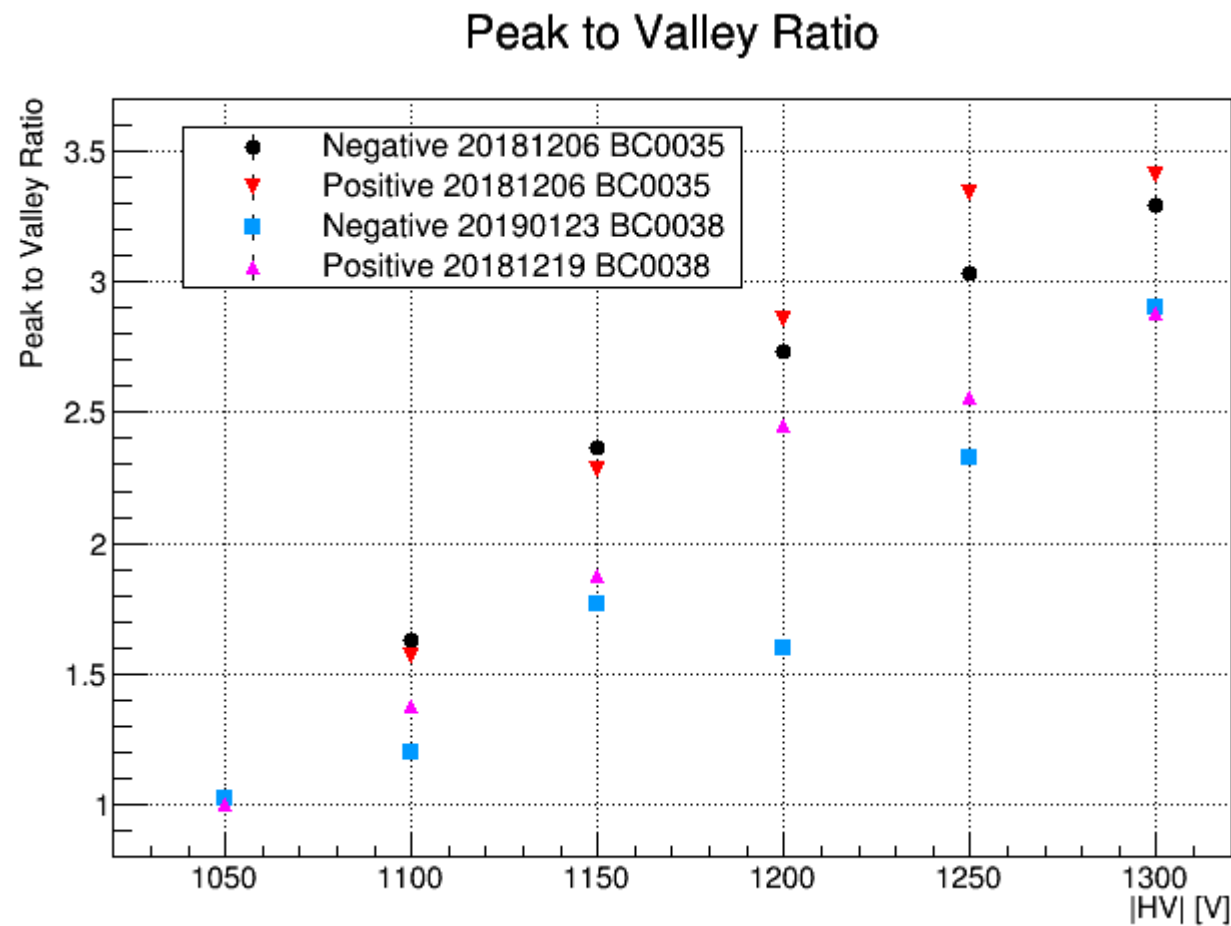
Gain



- Gain

- # of electrons at the anode when 1 p.e. is generated on the photocathode
- = 1.0×10^7 @1172 V (BC0035)
 - We couldn't find significant difference btw Negative and Positive HV.
 - $\text{Gain(BC0035)} / \text{Gain(BC0038)} \sim 1.4$ @ 1250 V

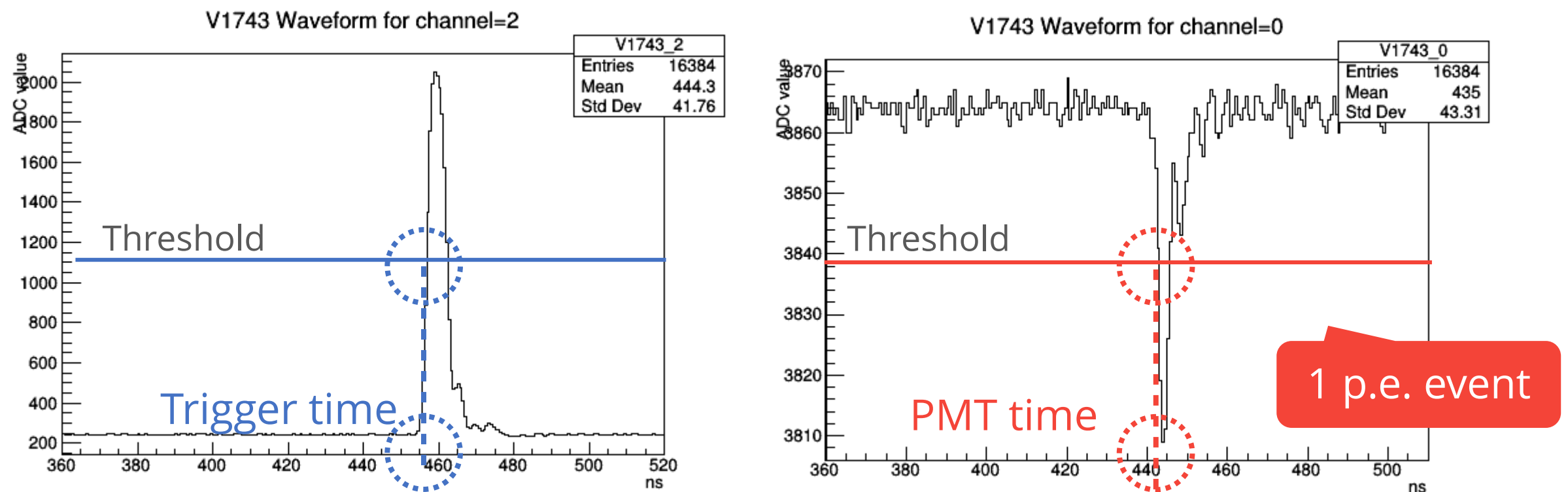
Peak-to-Valley ratio



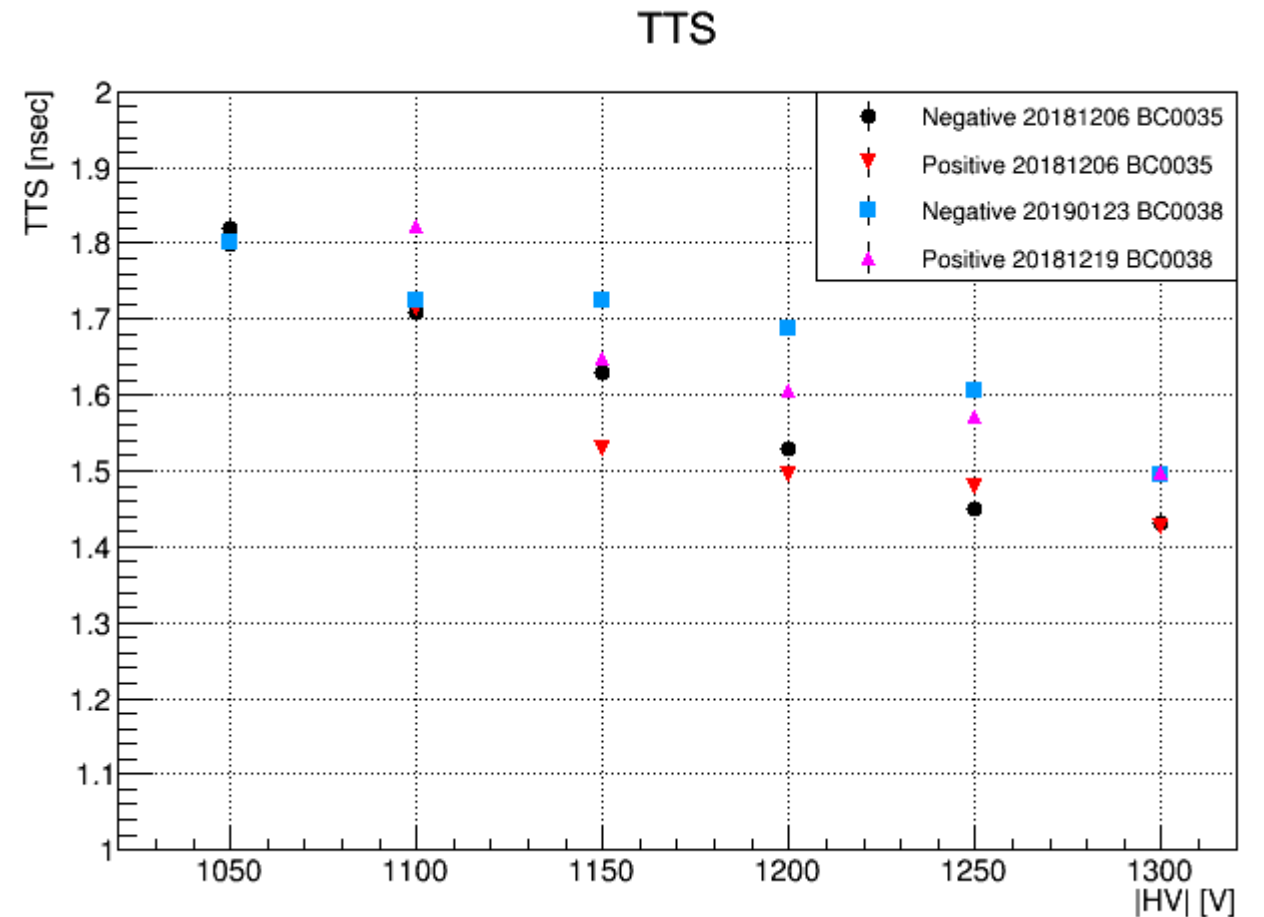
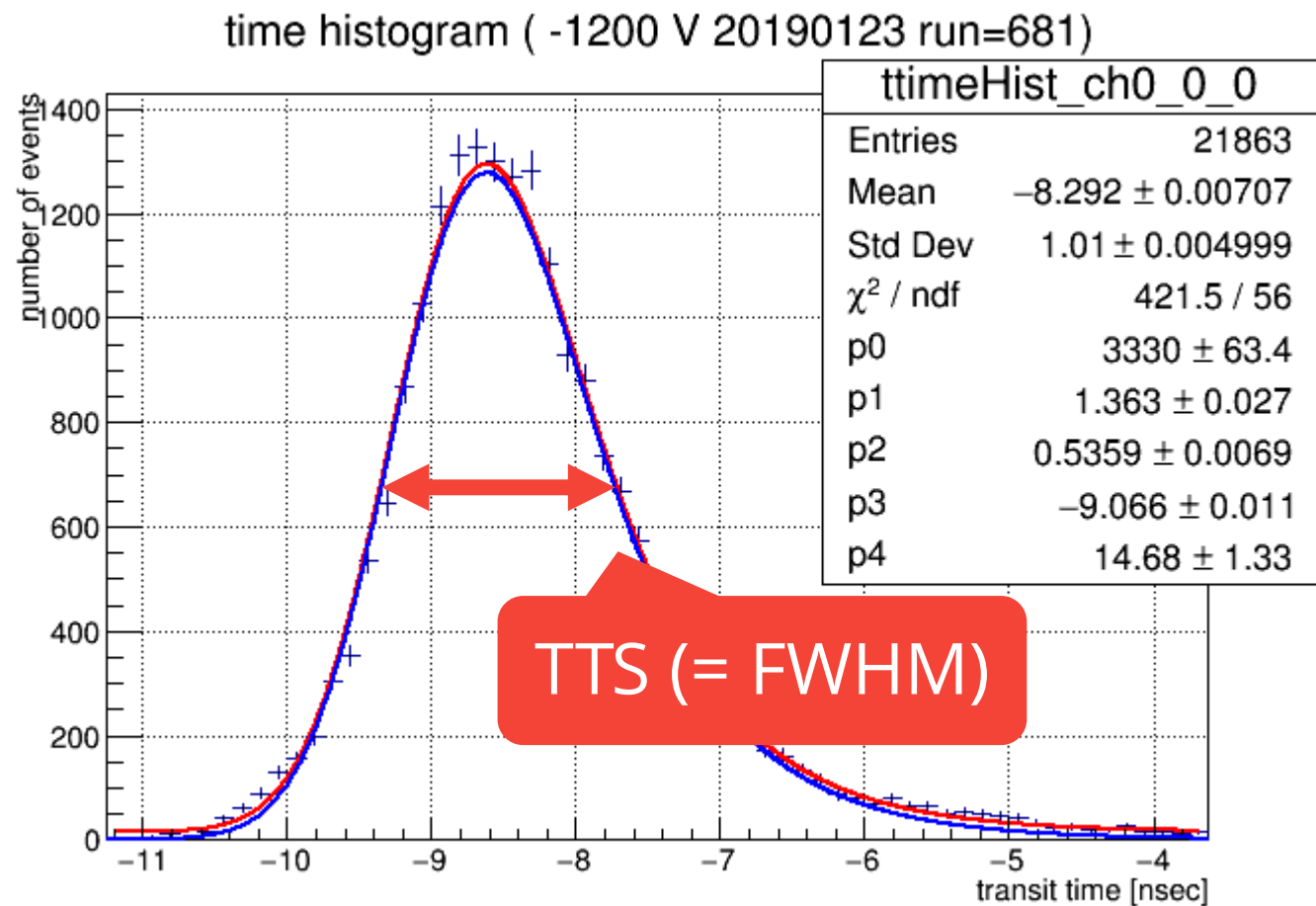
- Peak-to-Valley ratio is given by $\frac{\text{value at } Q_1}{\text{minimum value btw } Q_0 \text{ and } Q_1}$
 - using the value of the fitting function
 - Q_0 and Q_1 is the mean of pedestal and 1 p.e. distribution, respectively
- The HV in actual operation could be set above 1250 V.

TTS: Transit Time Spread

- Transit Time: TT
 - Flight time of electrons from photocathode to anode
- TTS: Calculate as FWHM of TT histogram

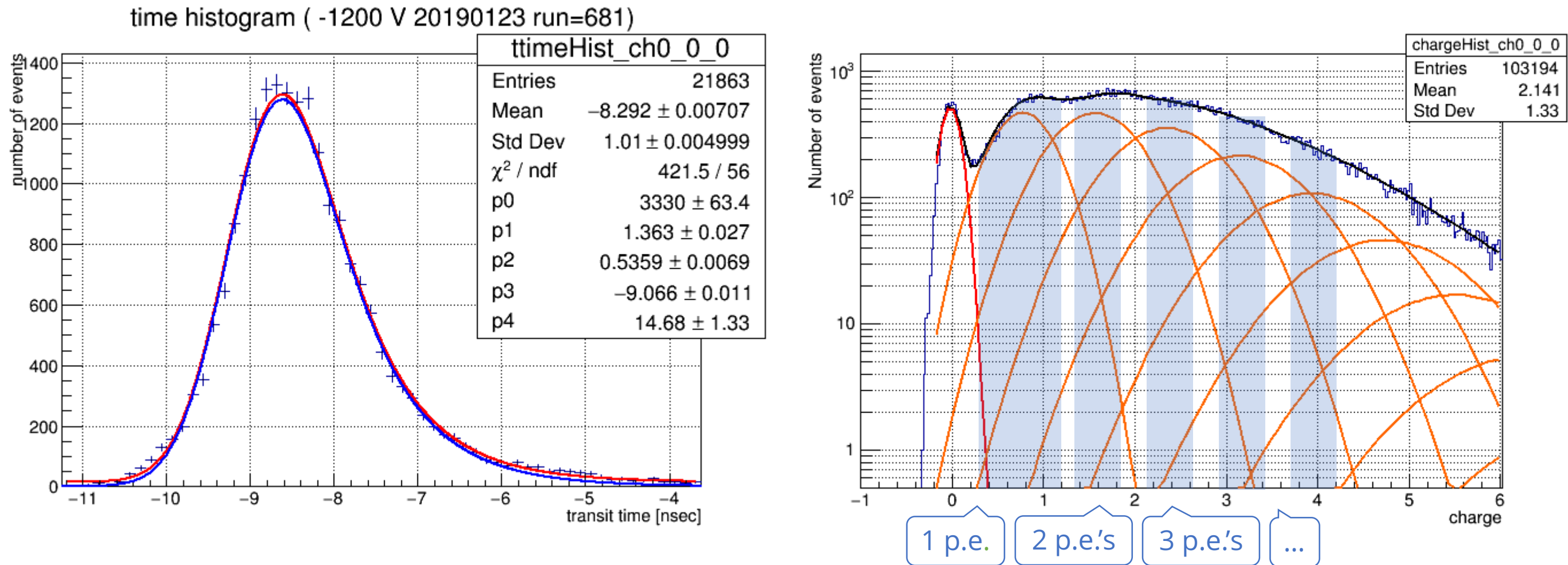


- Threshold = $1/2 \times (\text{noise average} + \text{peak max/min})$
 - like Constant Fraction Discriminator
- TT = PMT time - Trigger time, for 1 p.e. events
 - use the events where one photoelectron is generated on the photocathode.



- TT distribution: Exponentially modified Gaussian distribution
 - FWHM is directly gained by looking for the position with half the value of the peak, not by using some mathematical formula.
- $TTS < 1.65$ nsec above 1250 V
 - BC0035 has better TTS than BC0038

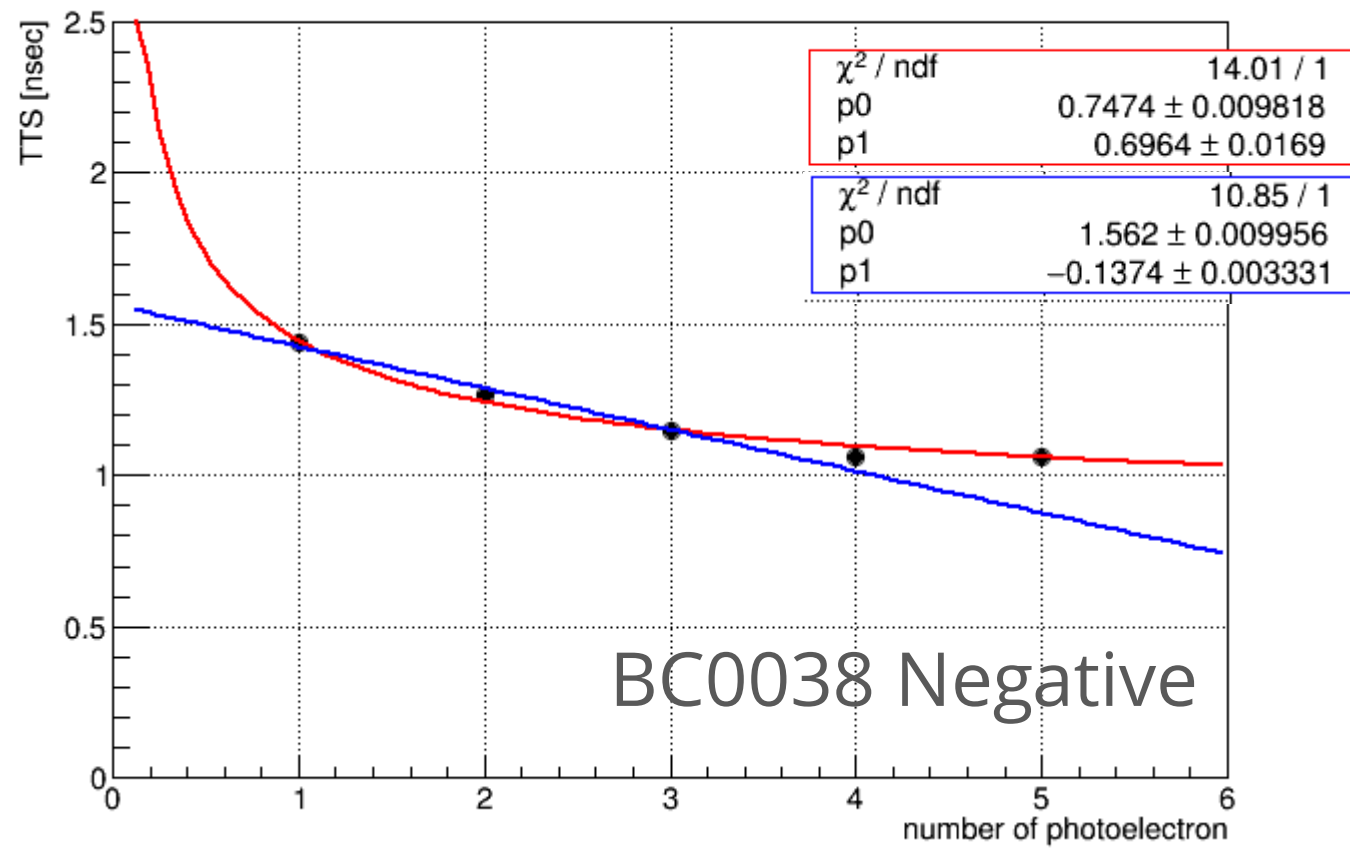
TTS: number of p.e.'s



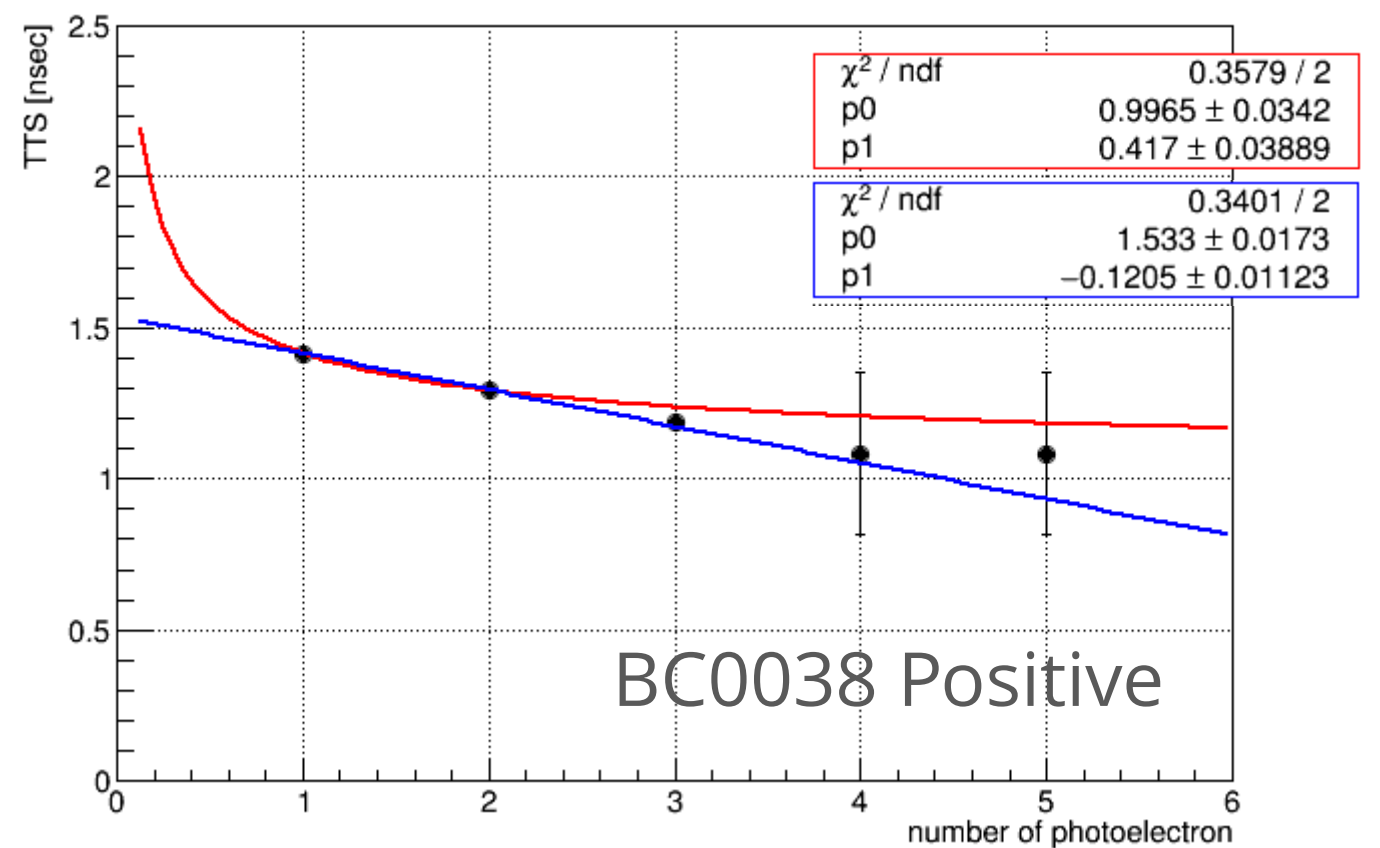
- When creating a TT histogram of $n > 1$ p.e., the corresponding events are extracted to satisfy $nQ_1 \pm 0.5\sigma_1$ (blue area),
 - where Q_1 and σ_1 are mean and sigma of 1 pe peak.
 - $Q_1 \pm \sigma_1$ for 1 p.e. events extraction.
- The overlap effect of n p.e. peaks is not considered
 - this might cause worse fit result
 - but we can see the curve of $1/\sqrt{x}$

TTS: # of p.e.'s: $p[0]+p[1]/\sqrt{x}$, $p[0]+p[1]*x$

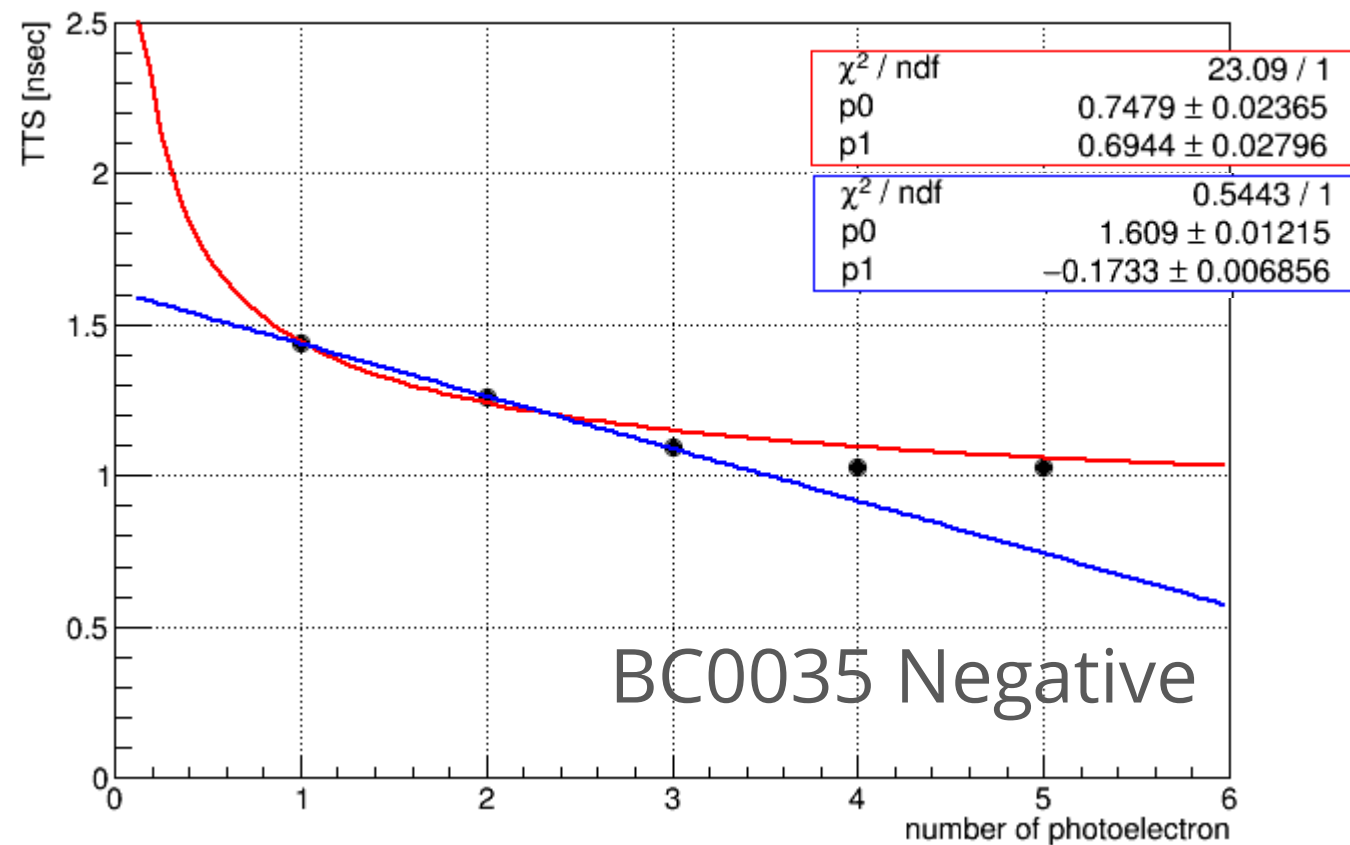
TTS (-1200 HV 20181219 run=638)



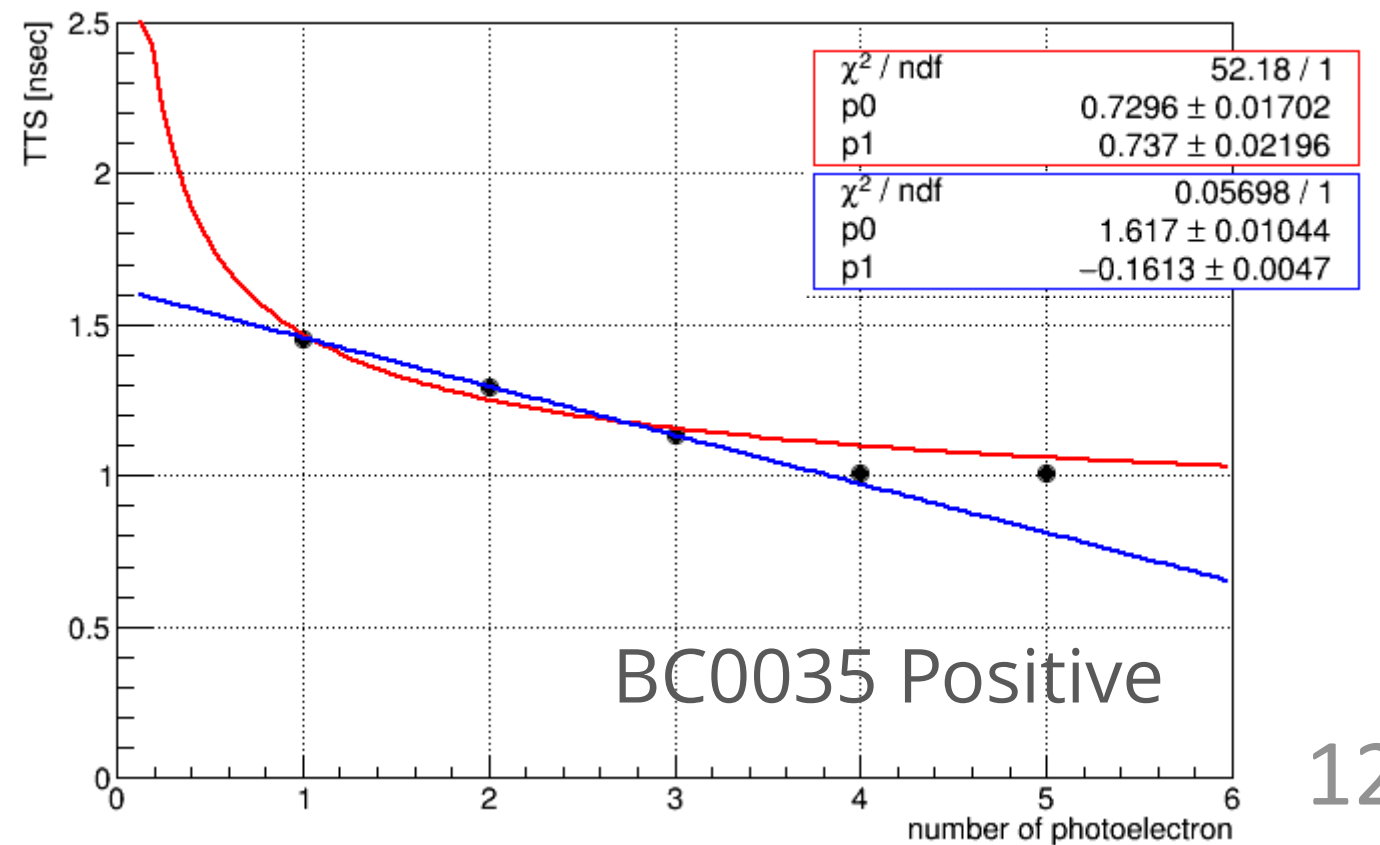
TTS (1200 HV 20181219 run=637)



TTS (-1200 HV 20181219 run=628)



TTS (1200 HV 20181219 run=629)

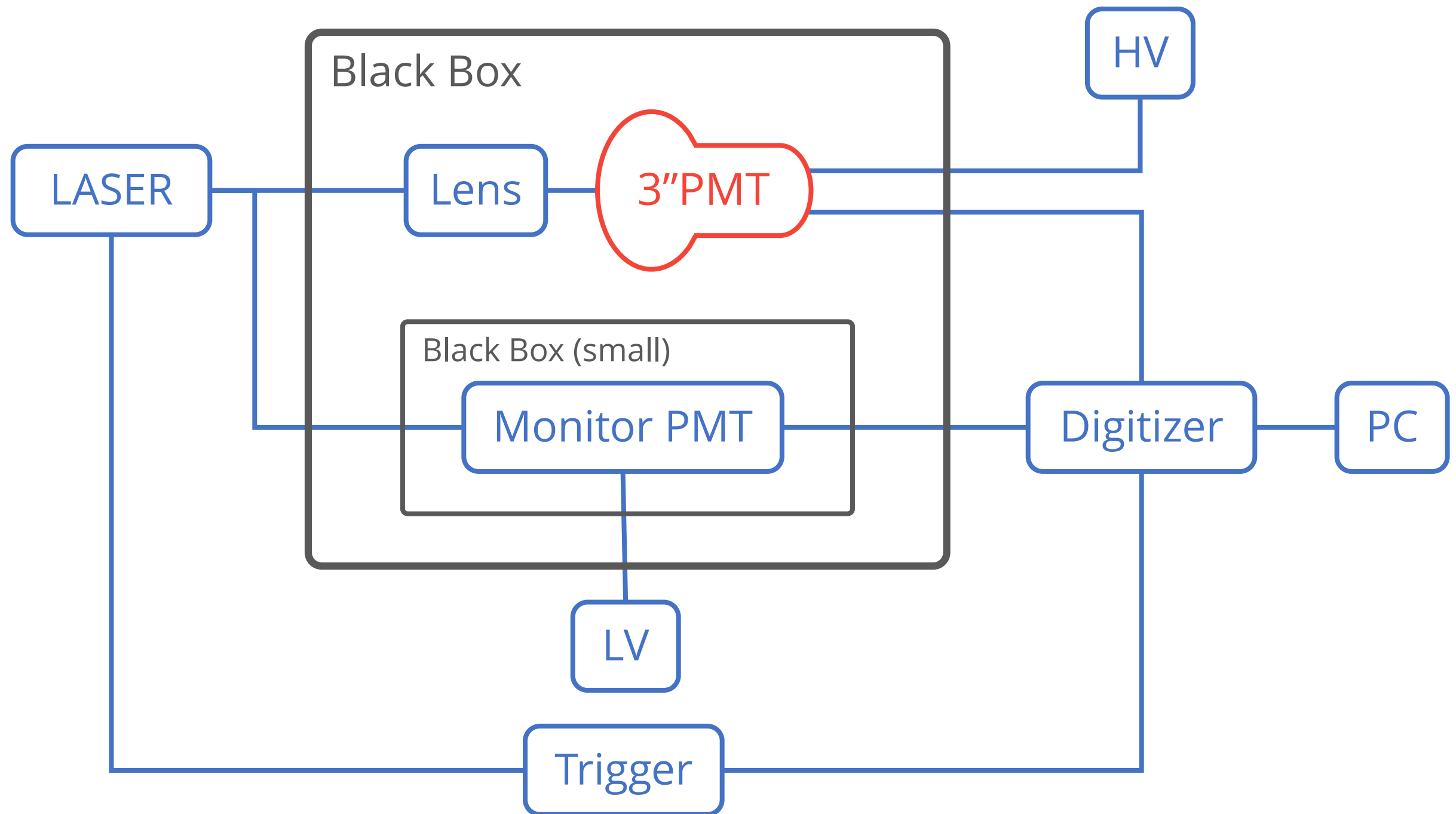


Summary

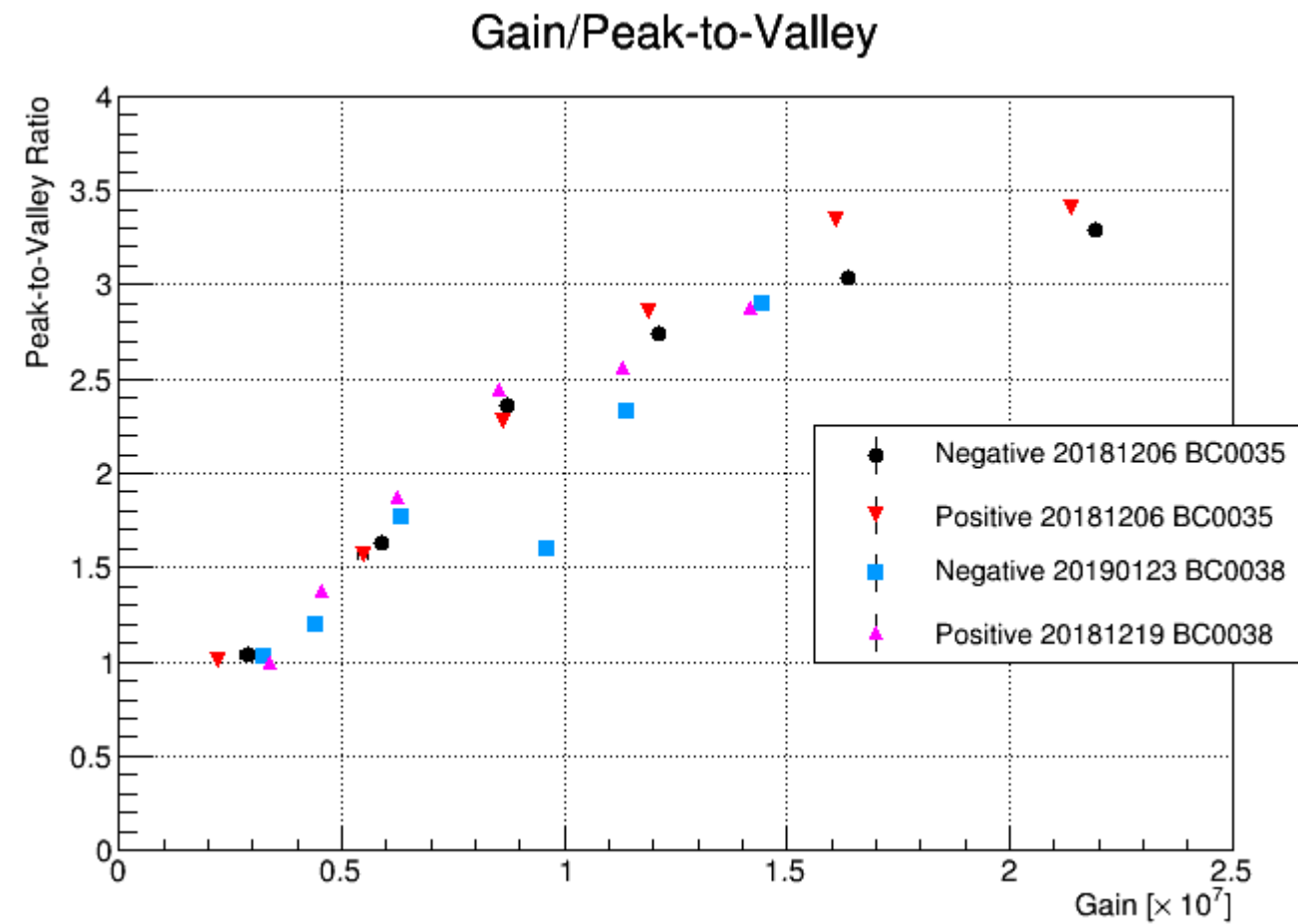
- Uniform light source test of R14374 @IPMU
 - 3" PMT from Hamamatsu Photonics K.K.
 - Test on two serial number: BC0035 and BC0038
- Gain = 1.0×10^7 @1172 V (BC0035)
 - No significant difference btw Negative and Positive HV
- Peak-to-Valley ratio > 3.0 above 1250 V (BC0035)
 - above 1250 V is enough to separate noise and signal in this meas.
 - No significant difference btw Negative and Positive HV
- TTS < 1.65 nsec above 1250 V
- Dependence of TTS on photoelectron number n
 - the trend of $1/\sqrt{n}$ could be seen

Back up

Schematic of the set up

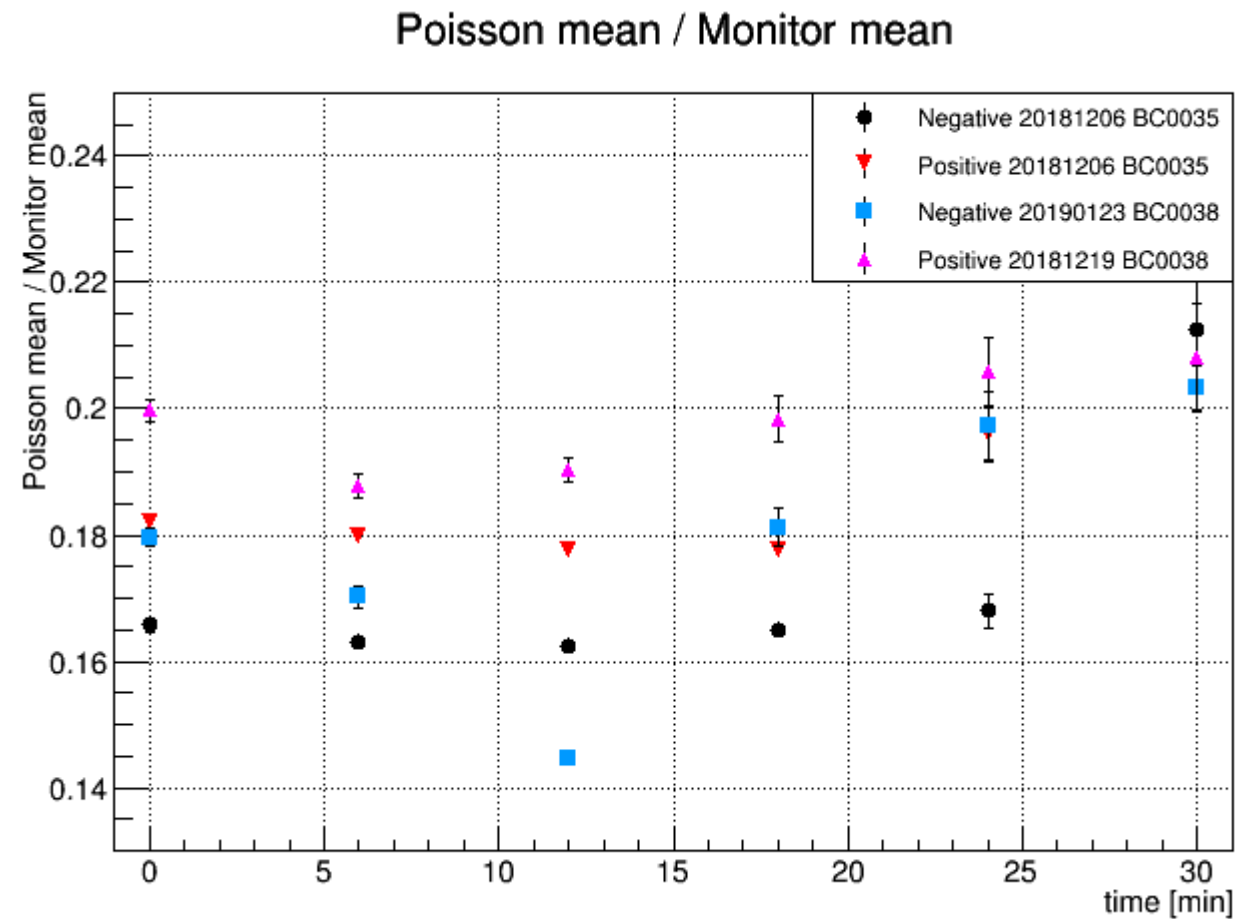


Gain vs. Peak-to-Valley Ratio



- There is no difference btw Negative and Positive HV

Poisson mean



- Poisson mean should be stable
 - Poisson mean: the fitted parameter
 - Monitor mean: the mean of histogram
 - x-axis(time) is roughly estimated
 - the measurements were done in turn from 1300 V to 1000 V

Fitting function: Charge histogram

- Number of photoelectron: Poisson distribution
- Output fluctuation: Gaussian distribution

$$arg = x - Q_0$$

$$S_{ped} = \frac{1 - W}{\sqrt{2\pi}\sigma_0} \exp\left(-\frac{1}{2} \left(\frac{arg}{\sigma_0}\right)^2 - \mu\right)$$

p0	p1	p2	p3	p4
Q_0	σ_0	W	α	μ

$$S_{noise} = \alpha W \exp(-\alpha \cdot arg - \mu), \quad 0 \text{ (if } arg < 0)$$

p5	p6	p7	p8
σ_1	Q_1	Q_{sh}	Norm

$$S_{sig1} = \frac{\mu^k e^{-\mu}}{\sqrt{2\pi}\sigma_1} \exp\left(-\frac{1}{2} \left(\frac{arg - Q_1 - Q_{sh}}{\sigma_1}\right)^2\right)$$

$$S_{sigN} = \sum_{n=2}^{10} \frac{\mu^k e^{-\mu}}{n!} \cdot \frac{1}{\sqrt{2\pi n}\sigma_1} \exp\left(-\frac{1}{2n} \left(\frac{arg - nQ_1 - Q_{sh}}{\sigma_1}\right)^2\right)$$

$$\sigma_1 \rightarrow \sqrt{\sum_{k=1}^n \sigma_1} = \sqrt{n}\sigma_1$$

Fitting function: Transit Time histogram

- Convolution of Gaussian and exponential:

$$h(x) = \frac{N}{2} \exp\left(-\lambda \cdot (x - \mu) + \frac{1}{2} \lambda^2 \sigma^2\right) \times \left[1 + \operatorname{erf}\left(\frac{(x - \mu) - \lambda \sigma^2}{\sqrt{2} \sigma}\right)\right] + C$$

p0	p1	p2	p3	p4
Norm	λ	σ	μ	C

error function: $\operatorname{erf}(x) = \frac{2}{\sqrt{\pi}} \int_0^x e^{-t^2} dt$

- Gaussian distribution : $f(x) = \frac{1}{\sqrt{2\pi}\sigma} \exp\left(-\frac{(x-\mu)^2}{2\sigma^2}\right)$,
Exponential : $g(x) = \exp(-\lambda x)$
- Then, $h(x) = f(x) * g(x) = \int_{-\infty}^{+\infty} dx' f(x') g(x - x')$
 - called Exponentially modified Gaussian distribution